

OC10 Rec'd PCT/PTO 21 MAR 2002

Docket No.: 2134-022

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

35  
07/9  
1-1703

In re Application of :  
Michael WOLLITZER :  
Serial No. n/a : Group Art Unit:  
Filed: Herewith : Examiner:  
For: MEASURING PROBE FOR MEASURING HIGH FREQUENCIES AND METHOD  
OF PRODUCING THE SAME

PRELIMINARY AMENDMENT

Assistant Commissioner for Patents  
Washington, D. C. 20231

Sir:

Prior to examination on the merits, please amend the  
referenced application as follows:

IN THE CLAIMS:

Please amend claims 1-6 as follows:

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- a/ 1. (amended) Measuring probe for measuring high frequencies,  
comprising a contact end for contacting planar structures and a co-  
axial cable end for connection to a co-axial cable; a co-planar  
conductor structure having at least two conductors arranged between  
the contact end and the co-axial cable end; a dielectric for  
mounting the co-planar conductor structure, the dielectric being  
arranged on the co-planar conductor structure; the dielectric being  
arranged on at least one side of the co-planar conductor structure  
in a central section between, and spaced, in the direction of  
propagation, from the co-axial cable end and the contact end, each